

Title of Change:	Memo	Memory Products US8 Back End Site and Material Change.					
Proposed first ship date:	16 Au	16 August 2019					
Contact information:	Conta	Contact your local ON Semiconductor Sales Office or < <u>logic.fpcn@onsemi.com</u> >					
Samples:	Sampl Final F Sampl	Contact your local ON Semiconductor Sales Office or < <u>PCN.samples@onsemi.com</u> > Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.					
Additional Reliability Data:	Conta	ct your local ON Semiconductor Sales Office or	r < <u>Phine.Guevarra@onsemi.com</u> >.				
Type of notification:	to imp ON Se	lementation of the change.	FPCN) sent to customers. FPCNs are issued 90 da ed, unless an inquiry is made in writing within 30 d <u>ort@onsemi.com></u>				
Change Part Identification:	Affect	Affected product will be marked with new marking style					
Change Category:	🗌 Wa	✓ Test Change Other					
Change Sub-Category(s): Manufacturing Site Addi Manufacturing Site Trans Manufacturing Process C Sites Affected: Description and Purpose: Qualify and transfer to a new s	er ange ON Se ON Se	 Material Change Product specific change miconductor Sites: remban, Malaysia to increase capacity. 	 Datasheet/Product Doc change Shipping/Packaging/Marking Other: External Foundry/Subcon Sites: Subcon Thailand 				
		Before Change	After Change				
Material to be		(Existing flow)	(new flow)				
Assy Si	e	ON Seremban Malaysia	Subcon Thailand				
Mold Comp	ound	MC SUMITOMO EME-G600FB	Molding Compound G600				
Lead fra	ne	AG STRIPE OVER D005	LF; PPF+ME2; US8; DAP 59x38				
Die Atta	ch	DA EN4370K3 SNAP CURE NON-C	Non-Conductive DAF, HR-5140				
Platin		100% Sn	Preplated				



		From		То	
	Product marking change	MARKING DIAGRAM 8 LR M - 1 LR =Device Code, M = D a Dot(.)=Lead Free Pact	tte Code,	Device Code, A= Assy lo Code, Y=Year Code, W = Code	
-		/TG 51871, S51869, I51156 and I489	941		
Tes	st Specificati	on C	Condition		Results
HTC	DL JESD22-A1	08 T	Ta= 125°C		0/80
HTS	SL JESD22-A1	03 Т	Ta= 150°C		0/80
TC	JESD22-A1	04 Ta= -6	Ta= -65°C to + 150°C		0/80
HAS	ST JESD22-A1	10 130°C, 85%	130°C, 85% RH, 18.8psig, bias		0/80
uHAS	ST JESD22-A1	18 130°C, 85% R	130°C, 85% RH, 18.8psig, unbiased		0/80
PC	J-STD-020 JESI	D-A113 MSI	MSL 1 @ 260°C		0/240
SD	JSTD002	Ta =	Ta = 245C, 10 sec		0/ 15
RSH	H JESD22- B1	.06 Ta =	Ta = 265C, 10 sec		0/30
impact on e of Affected e: Only the s	tandard (off the shelf)	ic. part numbers are listed in the pa il notification, or on the PCN Cu		rts affected by this PCN	are shown in the custom
	Part Num	ber		Qualification Veh	icle
	Part Num N24C08UI				icle
		DTG		Qualification Veh	icle
	N24C08UI	DTG DTG			icle
	N24C08UI N24C02UI	DTG DTG DTG			icle